

MS/RF PCM/PROCESS CHECKLIST SUB-WORKING GROUP MINUTES

Date: May 20, 2009
Location: Teleconference
Time: 10:00am (Pacific)
Participants:

Chelsea Boone – GSA
David Schwan – RF Micro Devices (RFMD)
Thomas Moerth – austriamicrosystems AG
Jay Seaton – Evolutionary Operations Consulting
Hugues Lafontaine – SiGe Semiconductor

Meeting Purpose:

- To gather feedback on how the Sub-Working Group should go about developing a checklist that will help in communicating basic process parameters and criteria for mixed-signal and RF processes.

End Result/Conclusions:

- There is a minimal number of measurements to correlate a yield on a chip.
- The PCM Checklist could target Logic processes.
- Instead of documenting all PCM aspects, we could focus on what is measured above and beyond what digital CMOS would measure.
- The PCM Checklist will be an appendix to the already developed Process Checklist.
- The PCM Checklist will show (1) a table of what is being measured (2) what the measurements are (3) definitions of what needs to be measured.
- Need to look at unit gain, leakage vs. transistor size, inductance, capacitors

Next Meeting: June 24, 2009, 10:00am (Pacific)